

**Search Notes**

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Examiner

Thien F. Tran

Applicant(s)/Patent under  
Reexamination

CHIOLA ET AL.

Art Unit

2811

**SEARCHED**

Class	Subclass	Date	Examiner
.257	471-473 481-486	10/12/2005	TT

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR